

The Effect of Package Pin Map on Signal Integrity for Test Applications

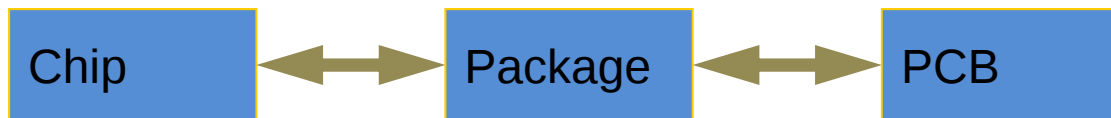
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Outline

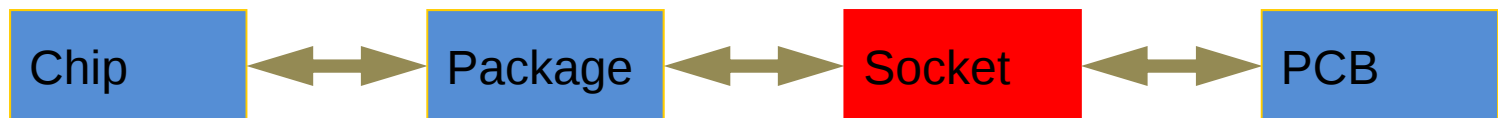
- ☐ Challenges
- ☐ Description of the case studies
- ☐ Bandwidth data
- ☐ Discussion
- ☐ Summary
- ☐ Future work

Challenges

- ❑ Package design is more challenging than ever due to faster IC (integrated circuit) speeds
- ❑ SI (signal integrity) analysis has become a crucial step of the package design
- ❑ The system level SI analysis is the best practice to ensure design success
 - ❑ Final product system:



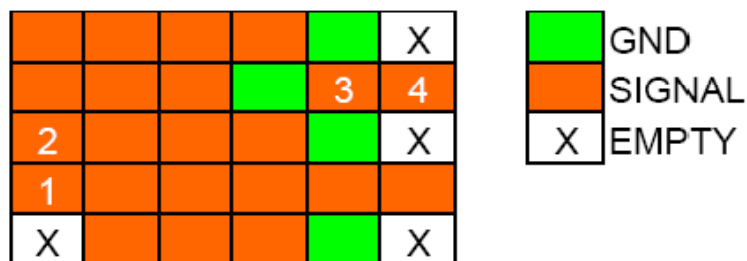
- ❑ Package test system:



- ☐ The system level analysis for final product is often conducted by system design engineers
- ☐ The system level analysis for package test is seldom conducted
- ☐ Signal degradation caused by socket compromises system performance in package test applications
- ☐ Package design aspects such as pin map has significant effect on the SI performance of the sockets

Description of the case studies

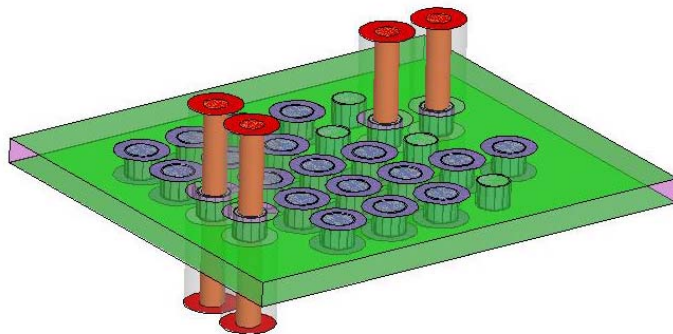
- ❑ Case 1, a real package pin map of a customer's product:



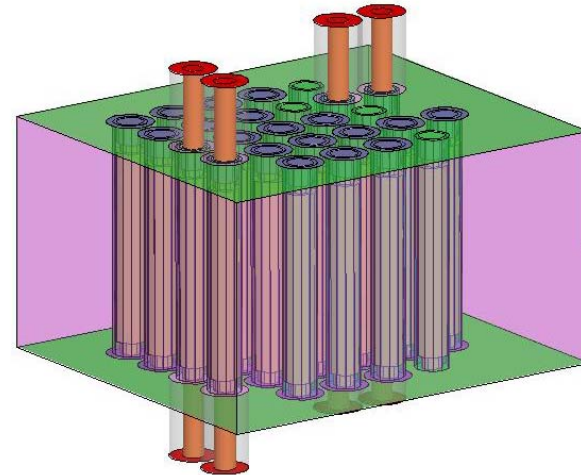
- ❑ Case 2, a revised pin map to improve the SI performance:



- ❑ Ansoft HFSS model setup
 - ❑ 1 mm pitch BGA, 0.4 mm ball height and 0.5 mm ball diameter
 - ❑ Co-axial waveports
 - ❑ 0.6 mm contact diameter, various contact lengths from 1 to 4 mm
 - ❑ Socket material dielectric constant: 3.5
- ❑ Assume -1 dB bandwidth of 5 GHz is required



HFSS model of package only



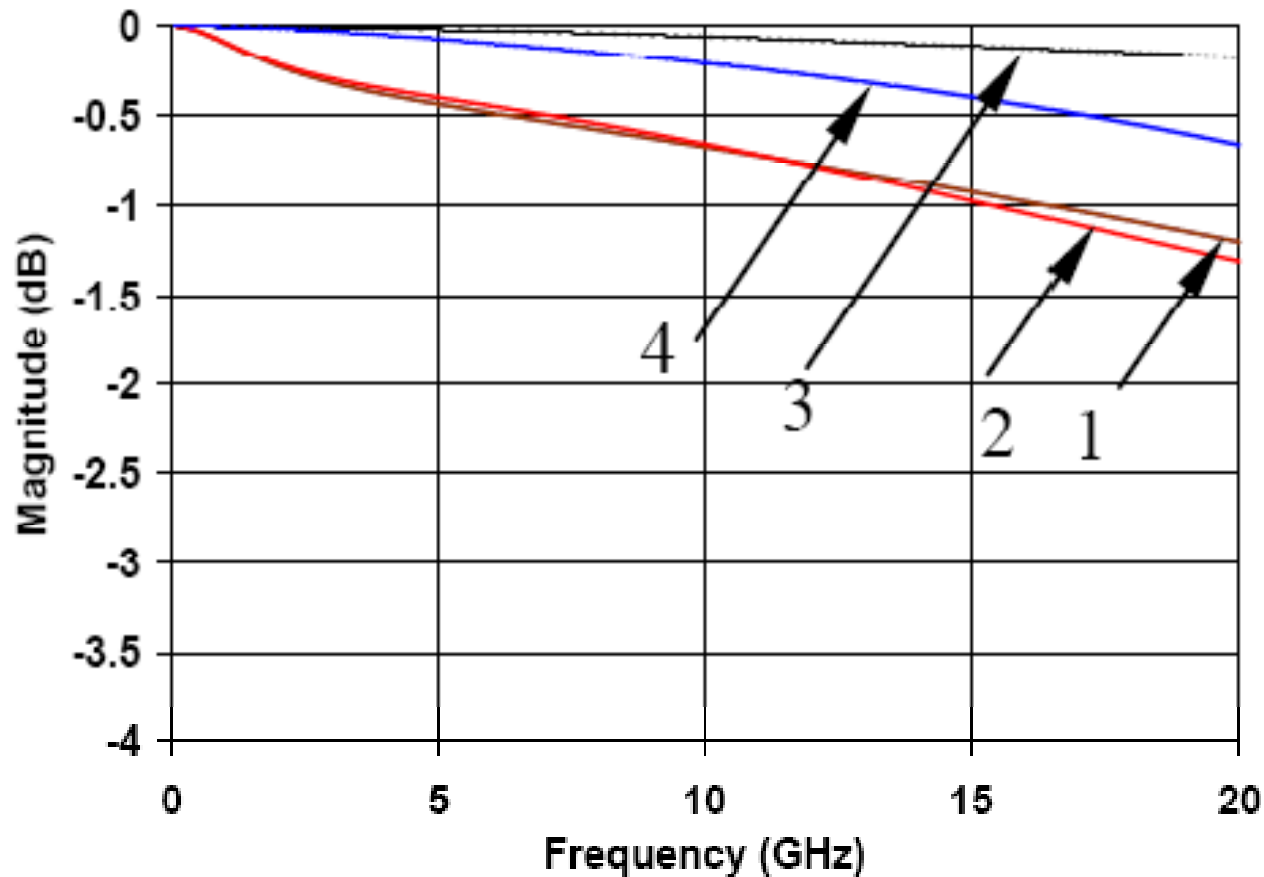
HFSS model of package and socket

Bandwidth data

2							
1							
X							

	GND
	SIGNAL
X	EMPTY

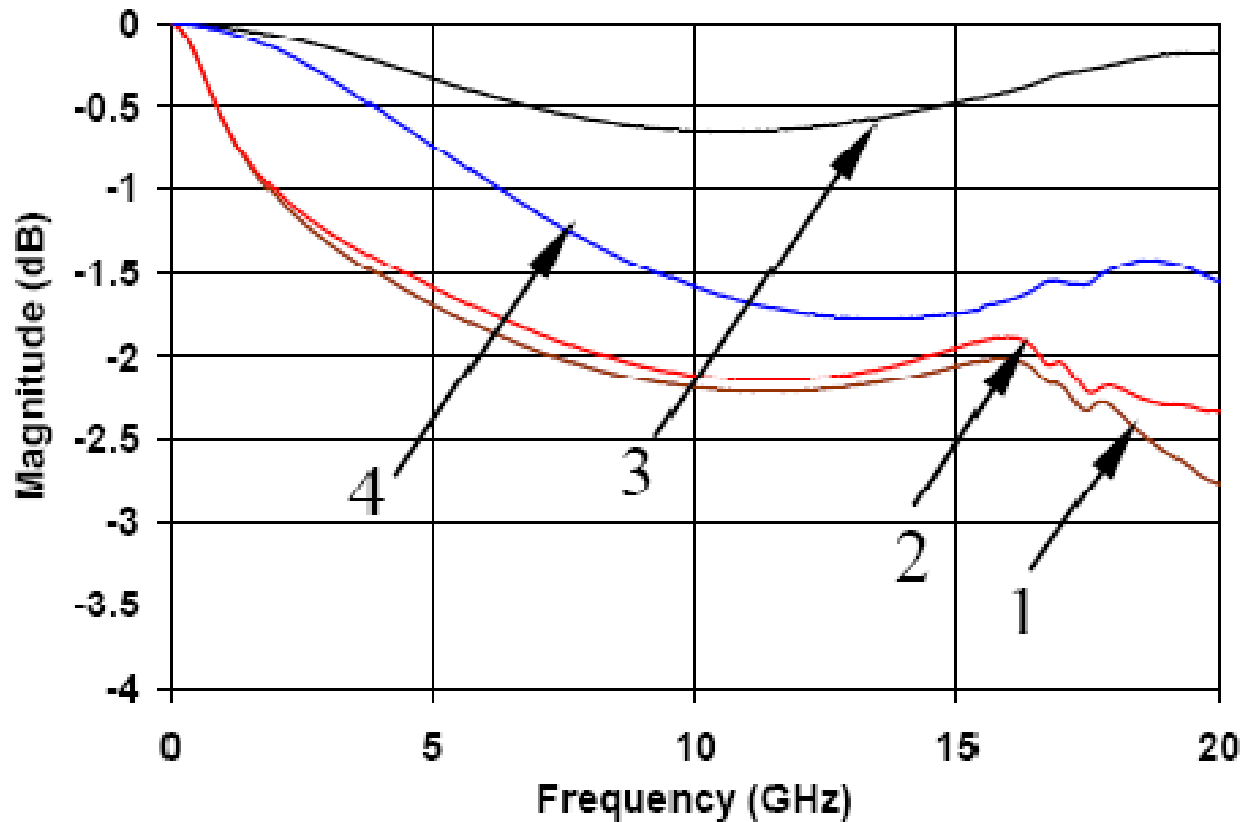
- Insertion losses of package only (case 1):
 - -1 dB bandwidth over 15 GHz for all pins under study



						X
					3	4
2						X
1						
X						X

	GND
	SIGNAL
X	EMPTY

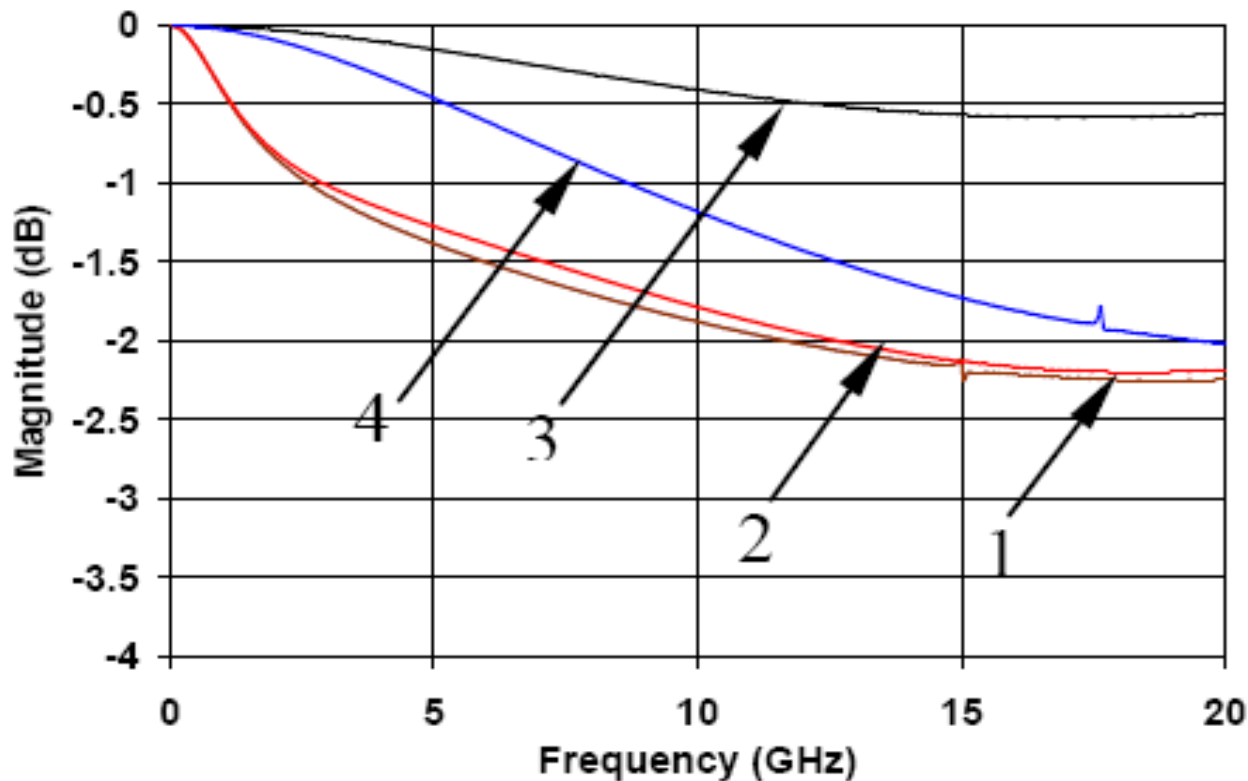
- ❑ Insertion losses of package and socket with 4 mm contacts (case 1):
 - ❑ -1 dB bandwidths of pin 1 and 2 fail 5 GHz requirement



						X
					3	4
2						X
1						
X						X

	GND
	SIGNAL
X	EMPTY

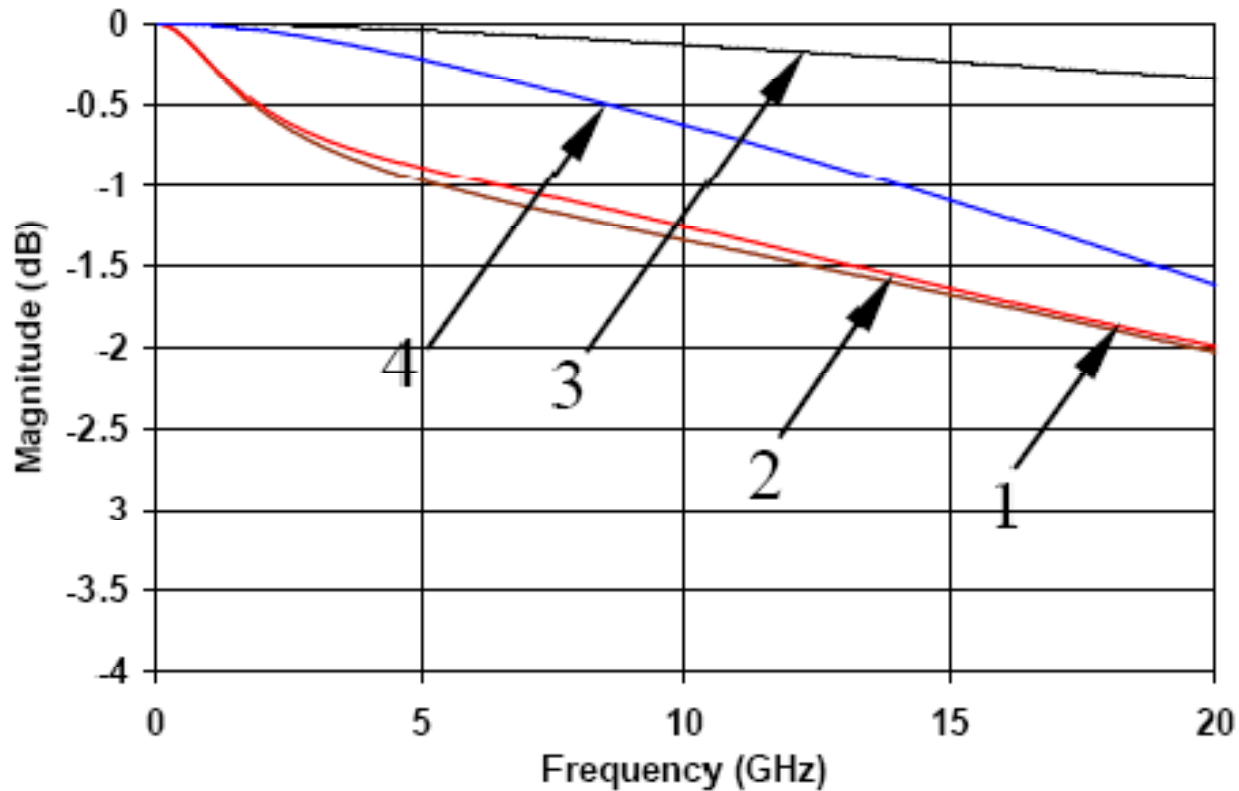
- ❑ Insertion losses of package and socket with 2.5 mm contacts (case 1):
 - ❑ -1 dB bandwidths of pin 1 and 2 still fail 5 GHz requirement



						X
					3	4
2						X
1						
X						X

	GND
	SIGNAL
X	EMPTY

- ❑ Insertion losses of package and socket with 1 mm contacts (case 1):
 - ❑ All pins meet 5 GHz requirement

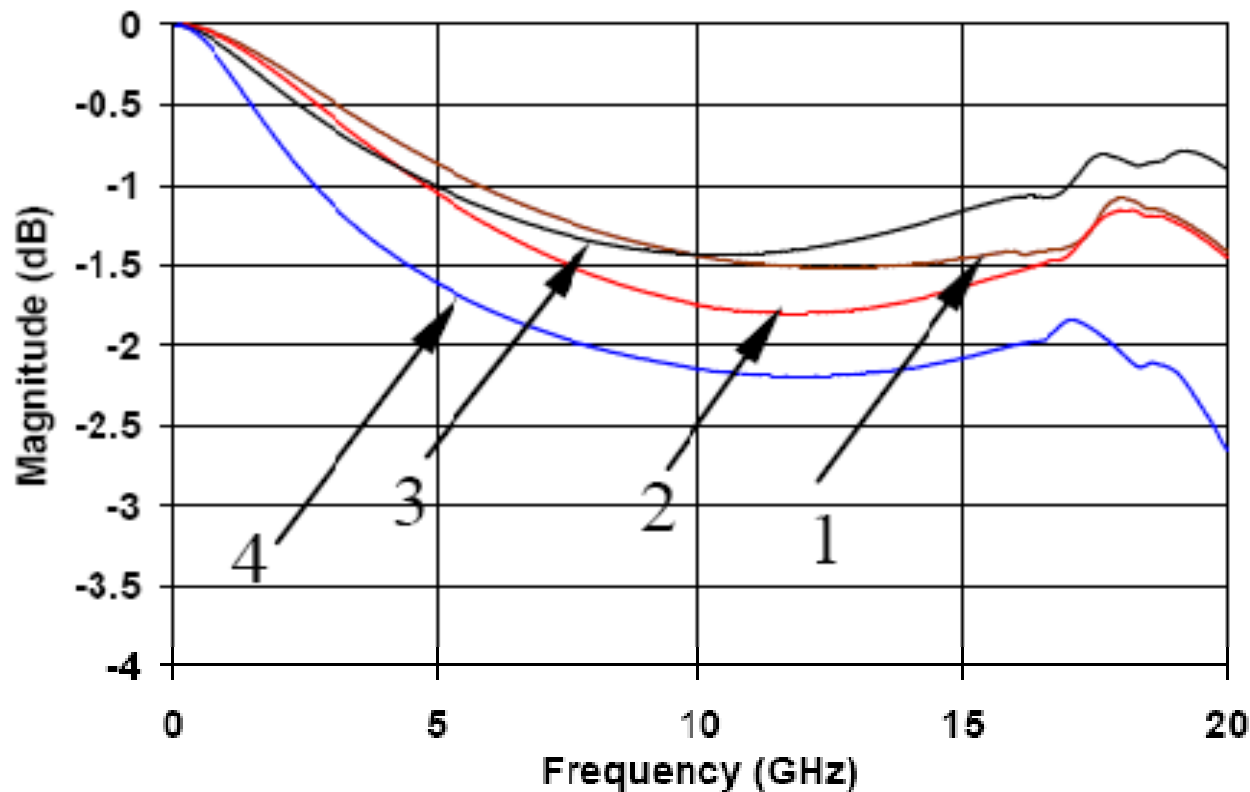


S21 plots

					X
				3	4
2					X
1					
X					X

	GND
	SIGNAL
X	EMPTY

- ❑ Insertion losses of package and socket with 4 mm contacts (case 2):
 - ❑ Pin 1 and 2 already meet 5 GHz bandwidth requirement
 - ❑ Pin 4 has much worse bandwidth in this case

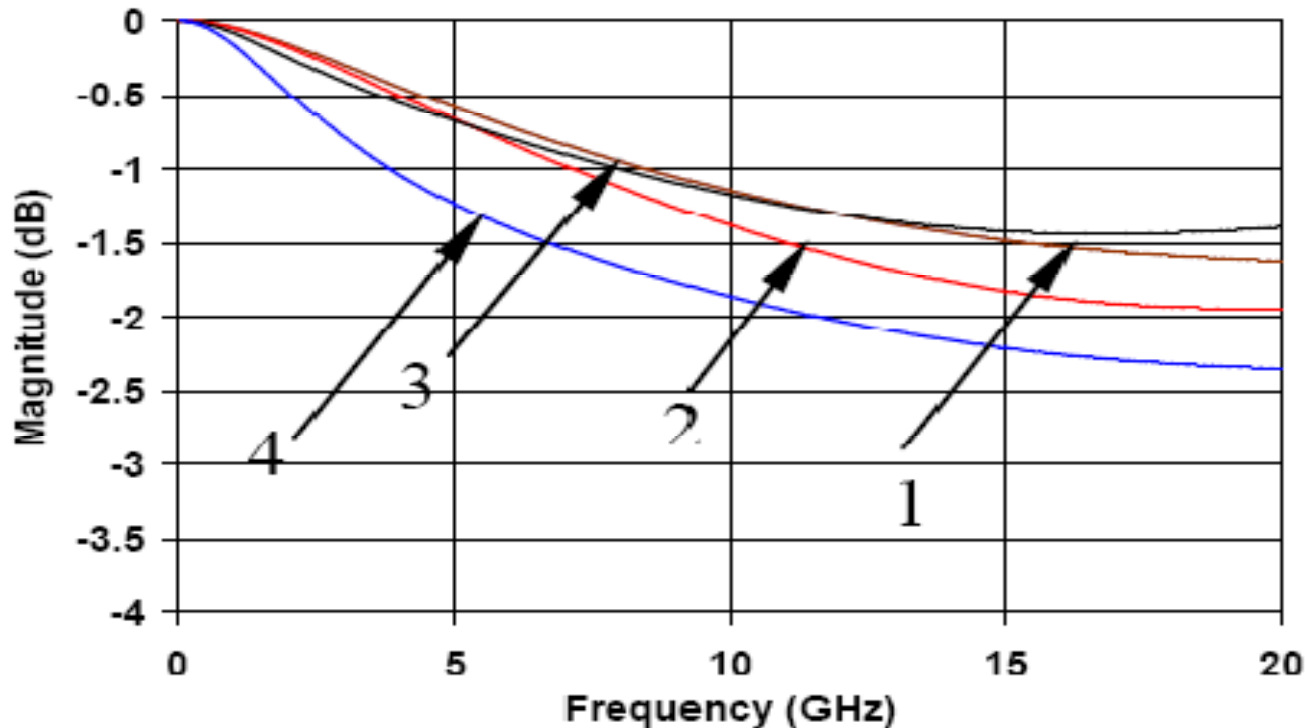


S21 Plots

					X
				3	4
2					X
1					
X					X

	GND
	SIGNAL
X	EMPTY

- ❑ Insertion losses of package and socket with 2.5 mm contacts (case 2):
 - ❑ Pin 1, 2 and 3 all pass the 5 GHz bandwidth requirement with comfortable margins
 - ❑ Pin 4 still fails the requirement

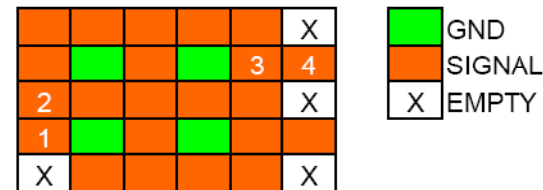


Discussion

- ☐ Case 1: The contact length need to be less than 1 mm in order to meet the bandwidth requirement
- ☐ Case 2: Except for pin 4, the contact length can be as much as 4 mm to meet bandwidth requirement
 - ☐ Adding an extra ground pin at empty location underneath pin 4 will improve its bandwidth beyond the requirement



Case 1



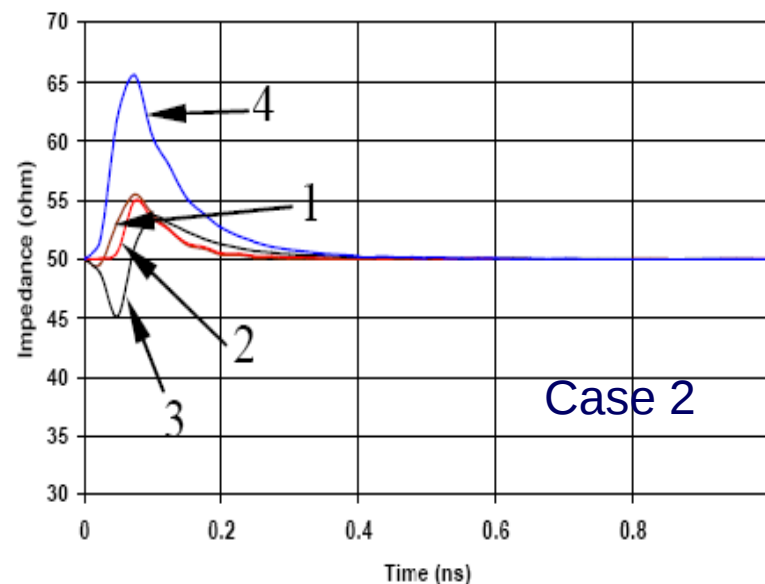
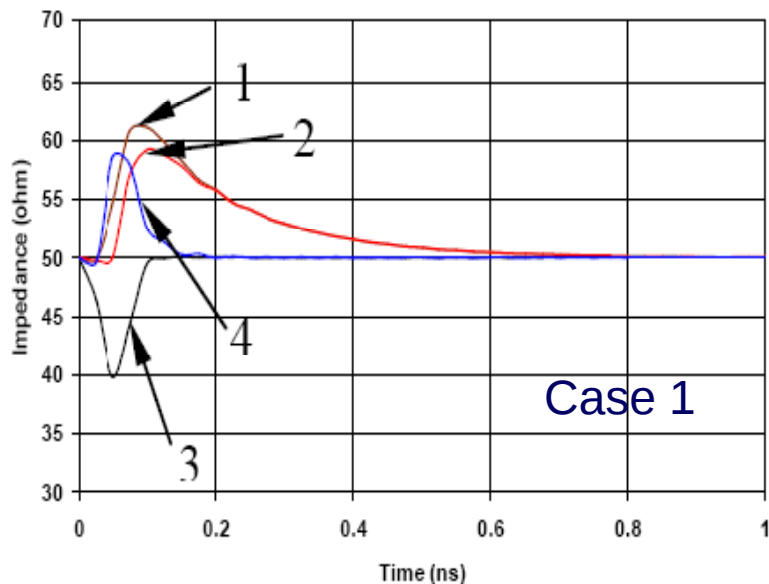
Case 2

- ☐ What caused improvement?
 - ☐ Being adjacent to ground pin improves the bandwidth
 - ☐ What really changed is the impedance

$$Z = \sqrt{\frac{L}{C}}$$

TDR Impedance Plots

□ TDR data:

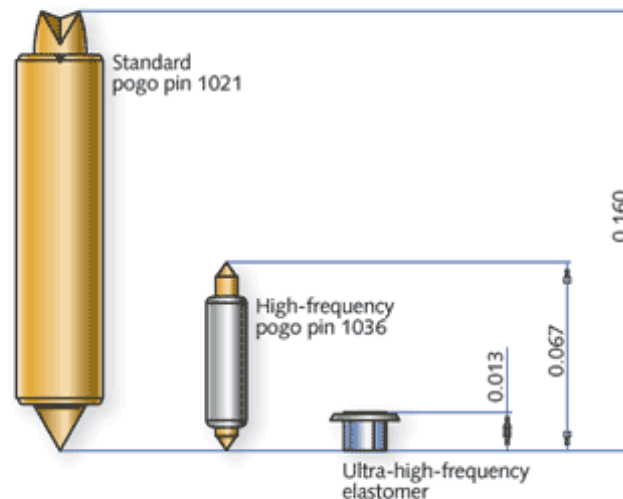


□ Reflection coefficient:

$$\Gamma = \frac{Z_1 - Z_0}{Z_1 + Z_0}$$

Contact Length

- ❑ What is the significance of the contact length?
 - ❑ 4 mm or above contact length can be easily achieved by conventional spring probe technology (low cost, reliable contact, long cycle life)
 - ❑ 2.5 mm contact length can be implemented by spring probe technology too (higher cost, less reliable contact, shorter cycle life)
 - ❑ 1 mm or below contact length only can be achieved by elastomer or stamping pin technology (poor contact, very short cycle life)



Summary



- ❑ Package pin map has major effect on SI performance of the socket
- ❑ When impedance mismatch is small, even longer contact length can deliver high signal bandwidth
- ❑ It is desirable to have at least one ground pin adjacent to signal pin so the impedance can be better controlled
- ❑ For inevitable impedance mismatch caused by package pin map, extremely short contact length is the only way to achieve high bandwidth
- ❑ Shorter contact length increase the overall cost for test

Future work



- ❑ The effect of the package design on signal integrity for test application is only limited on signal bandwidth in this presentation
- ❑ The effect of the package design on power delivery network is also very crucial, need to be investigated in the future
- ❑ Some important aspects for power integrity study:
 - ❑ Package stack up designs
 - ❑ Total number of power and ground pins
 - ❑ Decoupling scheme on package